

## Supporting Information

### **Expanded graphite/NiAl layered double hydroxide nanowires for ultra-sensitive, ultra-low detection limits and selective NO<sub>x</sub> gas detection at room temperature**

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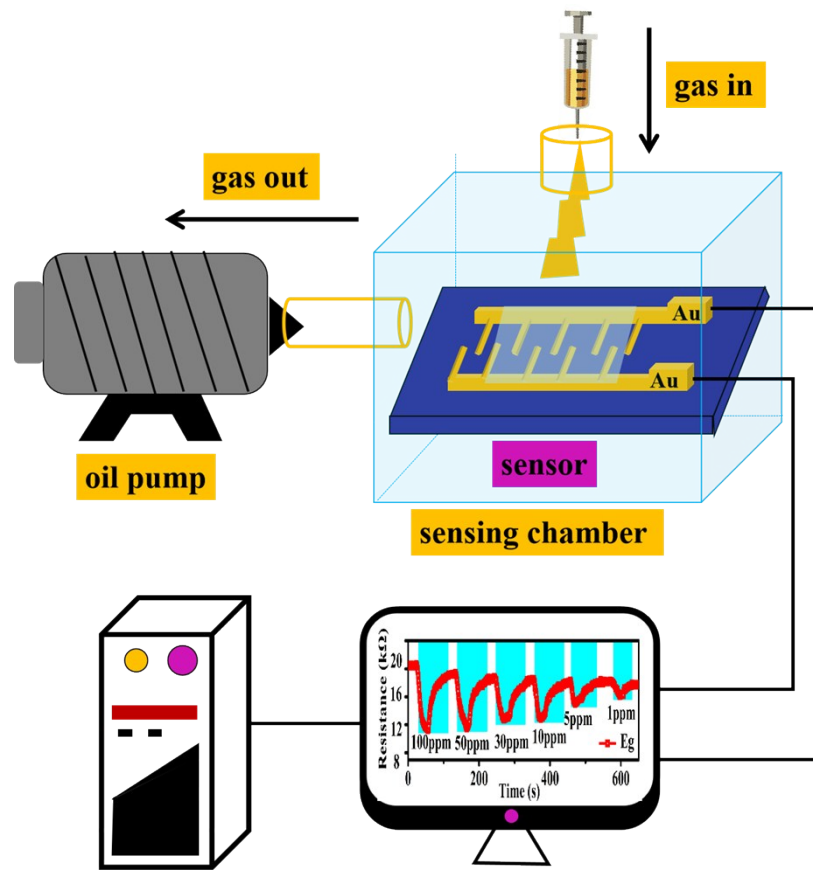
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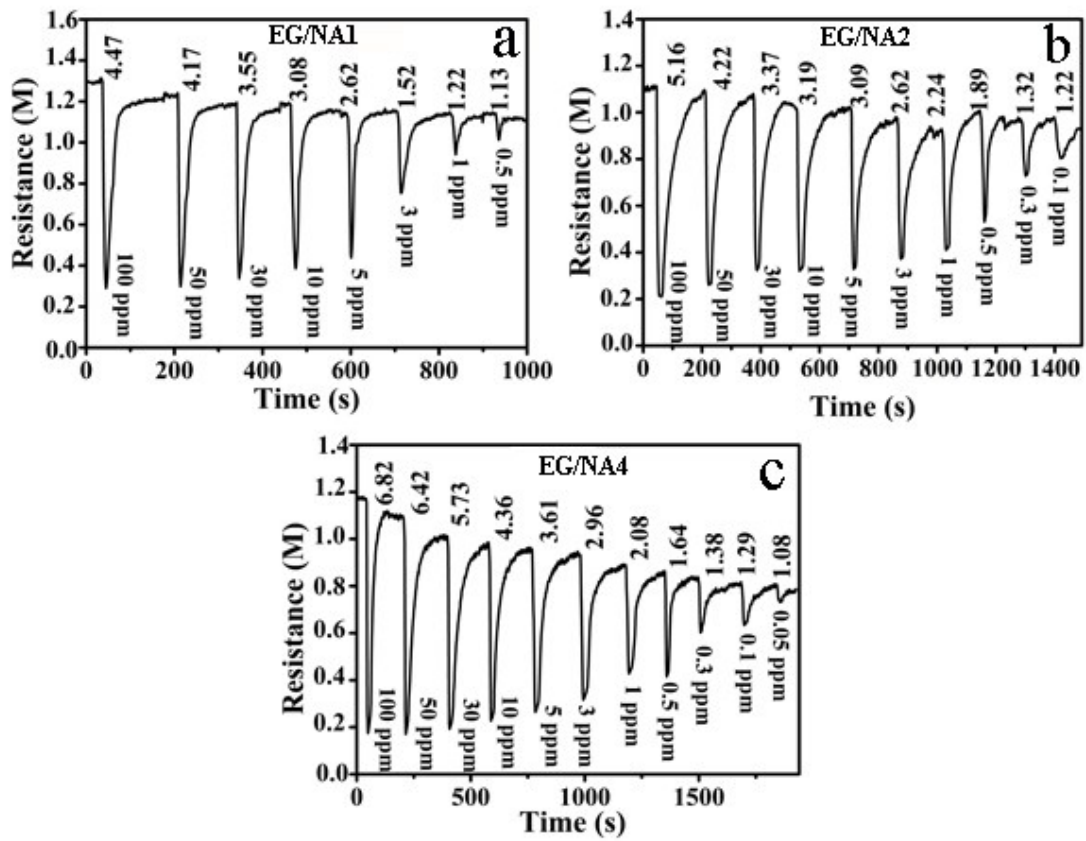
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**Fig. S1.** Gas sensing tests of thin-film sensors.



**Fig. S2** Dynamical response-recovery curves of (a) EG/NA1, (b) EG/NA2, and (c) EG/NA4 towards NO<sub>x</sub> at RT ( $24 \pm 2$  °C).

**Table S1** Response and response time of EG/NA samples to NO<sub>x</sub> at RT (24 ± 2 °C).

Sample	EG/NA1		EG/NA2		EG/NA3		EG/NA4	
	R	T/s	R	T/s	R	T/s	R	T/s
NO <sub>x</sub> (ppm)								
100	4.47	6.0	5.16	5.3	17.65	2.0	6.82	8.6
50	4.17	6.6	4.22	5.6	13.43	4.6	6.42	9.3
30	3.55	7.3	3.37	6.0	8.99	4.6	5.73	9.3
10	3.08	7.3	3.19	4.6	5.71	4.0	4.36	8.0
5	2.62	8.0	3.09	7.3	4.32	6.0	3.61	8.6
3	1.52	7.3	2.62	8.0	3.36	6.6	2.96	9.0
1	1.22	6.6	2.24	7.3	2.23	5.3	2.08	8.6
0.5	1.13	6.6	1.89	6.0	1.84	5.3	1.64	9.3
0.3	--	--	1.32	6.0	1.63	3.3	1.38	10
0.1	--	--	1.22	5.3	1.56	4.0	1.29	8.0
0.05	--	--	--	--	1.51	5.3	1.08	7.3
0.03	--	--	--	--	1.39	5.3	--	--
0.01	--	--	--	--	1.27	6.0	--	--

R: Response; T: Response time.

**Table S2** Response, response time and recovery time of EG, NiAl-LDH and EG/NA3 samples to NO<sub>x</sub> at RT (24 ± 2 °C).

Sample	EG			EG/NA3			NiAl-LDH		
NO <sub>x</sub> (ppm)	R	T <sub>1</sub> /s	T <sub>2</sub> /s	R	T <sub>1</sub> /s	T <sub>2</sub> /s	R	T <sub>1</sub> /s	T <sub>2</sub> /s
100	2.44	7.3	13.3	17.65	2.0	9.3	3.42	9.3	14
50	2.19	7.3	14.6	13.43	4.6	10	3.03	8.0	15.3
30	2.01	8.6	14.6	8.99	4.6	10	2.69	7.3	15.3
10	1.53	8.6	13.3	5.58	4.0	10.3	1.97	6.0	13.3
5	1.42	6.0	10.6	4.14	6.0	12.6	1.80	7.3	13.6
3	1.16	6.3	10.6	3.29	6.6	14	1.64	6.0	12
1	--	--	--	2.23	5.3	14	1.37	6.6	9.6
0.5	--	--	--	1.76	5.3	12.6	--	--	--
0.3	--	--	--	1.56	3.3	10	--	--	--
0.1	--	--	--	1.45	4.0	10	--	--	--
0.05	--	--	--	1.37	5.3	9.6	--	--	--
0.03	--	--	--	1.28	5.3	9.6	--	--	--
0.01	--	--	--	1.18	6.0	8.3	--	--	--

R: Response; T<sub>1</sub>: Response time; T<sub>2</sub>: Recovery time.

**Table S3** Carrier concentrations and fitted impedance parameters of EG, EG/NA3 and NiAl-LDH samples.

Samples	$R_{\Omega}$ ( $\Omega$ )	C ( $F\text{ cm}^{-2}$ )	$R_{ct}$ ( $\Omega$ )
EG	409.2	$4.56 \times 10^{-6}$	394.3
EG/NA3	1415	$7.81 \times 10^{-7}$	975.5
NiAl-LDH	4294	$2.01 \times 10^{-6}$	1931